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CONTENTS

VOLUME 11, ISSUE Nos 1–6

Issue No. 1, January–February

Editorial 1

Improving Quality in Iron Casting by Optimizing Sand Recycling: F. B. J. Sweeting, W. R. Thorpe and A. N. Pettitt 3

A Data Acquisition System for Machine Tool Condition Monitoring: P. R. Drake, A. D. Jennings, R. I. Grosvenor and D. Whittleton 15

Study of the Influence of Thermal Effects on the Electromigration Tests: S. Abdeslam and G. Lormand 27

On the ASTM Electromigration Test Structure Applied to Al–1%/TiN/Ti Bamboo Metal Lines: I. De Munari, M. Vanzi, A. Scorzoni and F. Fantini 33

Power-Temperature Cycle Accelerated Testing: L. J. Hart and K. L. Bruning 41

Study on Reliability Modelling of a Hydraulic Excavator System: S. K. Majumdar 49

NEWS DIGEST 65

CALL FOR PAPERS 69

INTERNATIONAL CALENDAR OF FORTHCOMING EVENTS 70

BOOK REVIEWS 74

Report Review 75

Issue No. 2, March–April

Editorial 77

SPC with Correlated Observations for the Chemical and Process Industries: C. M. Mastrangelo and D. C. Montgomery 79

Reliability Prediction of Pipes and Valves: J. E. Strutt, K. Allsopp and L. Ouchet 91

A Kalman Filtering Process Control Scheme with an Application in Semiconductor Short Run Manufacturing: E. Del Castillo and D. C. Montgomery 101

An Exploratory Study of a Neural Network Approach for Reliability Data Analysis: M. C. Liu, W. Kuo and T. Sastri 107

Economic Tolerance Design for Quality: A. Jeang 113

A Study of a Storage Reliability Estimation Problem: M. Zhao, M. Xie and Y. T. Zhang 123

Modelling Rail Vehicle Brake Pad Wearout and Replacement: G. A. Bohoris, A. Desai and D. J. Edge 129

NEWS DIGEST 139

Indexed or abstracted by Cambridge Scientific Abstracts, Engineering Index, INSPEC, Materials Information, Operations Research/Management Science, Research Alert, SciSearch, Quality Control & Applied Statistics and VINITI—U.S.S.R. Academy of Science

INTERNATIONAL CALENDAR OF FORTHCOMING EVENTS 142
Courses in Quality and Reliability 146
BOOK REVIEWS 148

Issue No. 3, May–June

Editorial 151
Obituary—David Spence Campbell 153
A Consumer Incentive Warranty Policy and Servicing Strategy for Products with Uncertain Quality: D. N. P. Murthy, I. Djamaludin and R. J. Wilson 155
Quality and 1/*f* Noise of Electronic Components: A. Konczakowska 165
An Alternative Method to Test for Randomness of a Process: D. S. Holmes and A. E. Mergen 171
Off-line Quality Control for V-process Castings: P. Kumar and J. L. Gaindhar 175
Optimal Reliability and Maintainability Allocation in Manufacturing Systems: R. Calabria, G. Pulcini and M. Rapone 183
A Shewart-like Charting Technique for High Yield Processes: W. Xie, M. Xie and T. N. Goh 189
Translation of the Baldrige Award Criteria to a Context More Accessible to Small Companies: R. H. Dunn 197
Reliability Analysis for the Design of an Inflator: S.-H. Teng and S.-Y. Ho 203
NEWS DIGEST 215
INTERNATIONAL CALENDAR OF FORTHCOMING EVENTS 218
BOOK REVIEWS 223

Issue No. 4, July–August

Special Issue: Papers presented at the European Symposium on Reliability of Electron Devices, Failure Physics and Analysis (ESREF '94), Glasgow, Scotland, October 1994
Guest Editor: G. M. Brydon

Editorial: G. M. Brydon 225
Critical Area Analysis for Design-based Yield Improvement of VLSI Circuits: D. Schmitt-Landsiedel, D. Keitel-Schulz, J. Khare, S. Griep and W. Maly 227
Upper Voltage and Temperature Limitations of Stress Conditions for Relevant Dielectric Breakdown Projections: R.-P. Vollertsen and W. W. Abadeeer 233
Write/Erase Degradation and Disturb Effects in Source-side Injection Flash EEPROM Devices: D. Wellekens, J. Van Houdt, G. Groeseneken, H. Maes and L. Faraone 239
Optical Ammeter for Integrated Circuit Characterization and Failure Analysis: W. Claeys, S. Dilhaire, D. Lewis, V. Quintard, T. Phan and J. L. Aucouturier 247
Voltage Contrast Studies on 0·5 μm Integrated Circuits by Scanning Force Microscopy: C. Böhm, J. Sprengepiel and E. Kubalek 253
Frequency Dependence of Degradation and Breakdown of Thin SiO_2 Films: M. Nafria, D. Yelamos, J. Suñe and X. Aymerich 257
A Method for the Calculation of the Soft-error Rate of Sub-μm Dynamic Logic CMOS Circuits: T. Juhnke, M.-P. Bringmann and H. Klar 263

Hot-carrier Reliability Lifetimes as Predicted by Berkeley's Model: A. Meehan, P. O'Sullivan, P. Hurley and A. Mathewson 269

Evaluation of the Hot-carrier-induced Offset Voltage of Differential Pairs in Analogue CMOS Circuits: R. Thewes, M. J. Kivi, K. F. Goser and W. Weber 273

Shape Changes of Voids in Bamboo Lines: A New Electromigration Failure Mechanism: O. Kraft, U. E. Möckl and E. Arzt 279

ESD Protection Elements during HBM Stress Tests—Further Numerical and Experimental Results: C. Russ, H. Gieser and K. Verhaege 285

Behaviour of Lasing Wavelength Change During Degradation in Buried-Heterostructure (BH)-Type DFB Laser: M. Fukuda, F. Kano, T. Kurosaki and J. Yoshida 295

Fracture Mechanical Characterization of IC-Device Interfaces: K. Burger 299

In Situ Failure Detection in Thick Film Multilayer Systems: J. Manca, L. De Schepper, W. De Ceuninck, M. D'Olieslaeger and L. M. Stals 307

NEWS DIGEST 313

INTERNATIONAL CALENDAR OF FORTHCOMING EVENTS 316

Courses in Quality and Reliability 319

BOOK REVIEWS 321

Issue No. 5 September–October

Editorial 323

Total Quality Control for a Surface Mount Technology Process for the Manufacture of Printed Circuit Board Assemblies: L.-Y. Chan and L. W.-T. Law 325

Gate Oxide Evaluations from High-*E* Tests: D. S. Peck 333

Measuring System and Software Reliability using an Automated Data Collection Process: B. Murphy and T. Gent 341

Control Charts for Processes Subject to Random Shocks: W. Xie, M. Xie and T. N. Goh 355

Proportional Hazards Modelling of Repairable Systems: D. Kumar 361

Computer Simulation for Quality and Reliability Engineering: S. Robinson and N. Higton ... 371

MATHEMATICAL CORNER 379

NEWS DIGEST 389

INTERNATIONAL CALENDAR OF FORTHCOMING EVENTS 392

BOOK REVIEWS 396

Issue No. 6, November–December

Special Issue on Safety Engineering
Guest Editor: Harry Fox

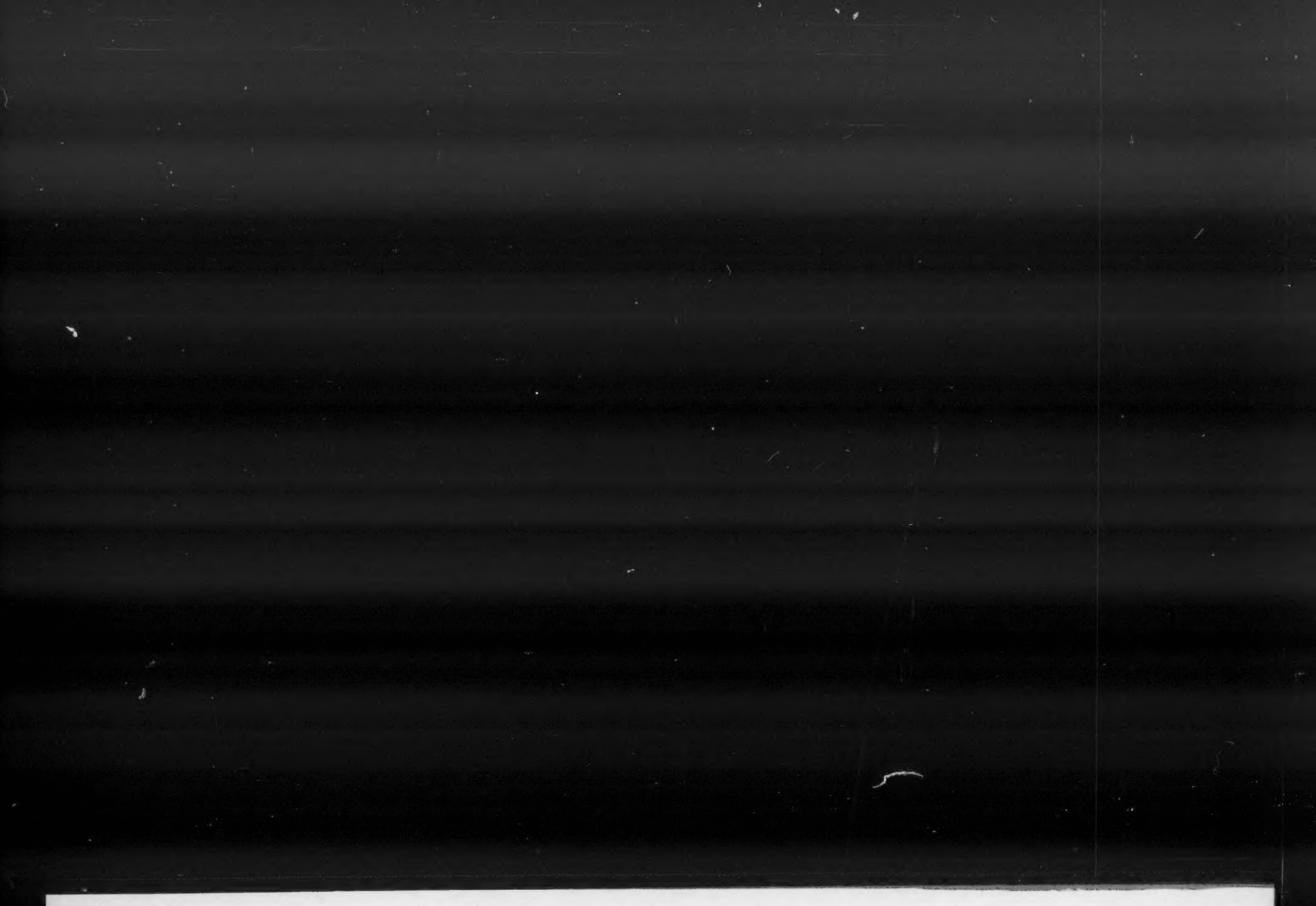
Editorial 397

Application of Hazard and Operability Studies to a Wide Range of Industries and Activities: B. W. Robinson 399

Software Safety Initiatives: S. J. Keene 403

Determination of Human Error Patterns: The Use of Published Results of Official Enquiries into System Failures: E. A. Bradley 411

Human–Computer Interaction in Safety Critical Systems: B. A. Leathley 429

Training Needs Analysis—A Human Factors Analysis Tool: C. W. Griffiths and A. Lees 435

Quantified Risk Assessment in Railway System Design and Operation: J. P. Haile 439
Risk Assessment of a New High Speed Railway: C. L. Leighton and C. R. Dennis 445
NEWS DIGEST 457
INTERNATIONAL CALENDAR OF FORTHCOMING EVENTS 460
Courses in Quality and Reliability 463
BOOK REVIEWS 465
Author Index 467
Key Word Index 469